

IN-SITU WEAR INDICATOR FOR NON-SELECTIVE MATERIAL REMOVAL SYSTEMS

ABSTRACT OF THE DISCLOSURE

An in-situ wear indicator for detecting wear to at least one selected part in a semiconductor manufacturing environment. The indicator is manufactured in a selected material with a selected thickness so that the indicator degrades upon exposure to the semiconductor manufacturing process at a fixed rate relative to the wear of the selected part. The indicator displays a visual indication of wear which is discernible by an automated detection device.